

FORM PTO-1449	SERIAL NO. 10/624,031	CASE NO. 10808/101
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)	FILING DATE July 21, 2003	GROUP ART UNIT 2824
APPLICANT(S): Frankowsky, Gerd		


REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
DN	A1	US 2003/0005353 A1	1/2/2003	Mullins, et al.	714/5	5/31/2002
DN	A2	US 6,539,506 B1	3/25/2003	Lammers, et al.	714/719	11/1/1999

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
DN	A3	EP 1 008 993 A2	6/14/2000	EP	G11C 29/00	No

EXAMINER INITIAL	OTHER ART - NON PATENT LITERATURE DOCUMENTS <small>(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.)</small>	
DN	A4	Tarr, M. et al., "Defect Analysis System Speeds Test and Repair of Redundant Memories," Electronics, VNU Business Publications, vol. 57, no. 1, January 12, 1984, pages 175-179.
DN	A5	International Search Report for counterpart international patent application number PCT/EP2004/07740, dated 11/9/2004, 7 pages.

EXAMINER 	DATE CONSIDERED 3/2/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.